TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSIV)

# 2SK3473

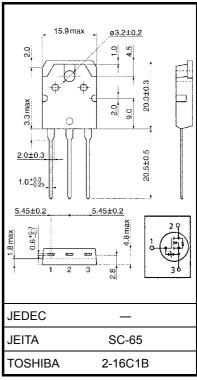
### **Switching Regulator Applications**

Unit: mm

- Low drain-source ON resistance: RDS (ON) =  $1.3 \Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 6.5S$  (typ.)
- Low leakage current:  $I_{DSS} = 100 \, \mu \, A \, (V_{DS} = 720 \, V)$
- Enhancement-mode:  $V_{th} = 2.0 \sim 4.0 \text{ V (VDS} = 10 \text{ V, ID} = 1 \text{ mA})$

### Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		$V_{DSS}$	900	V	
Drain-gate voltage ( $R_{GS} = 20 \text{ k}\Omega$ )		$V_{DGR}$	900	V	
Gate-source voltage		$V_{GSS}$	±30	V	
Drain current	DC (Note 1)	I <sub>D</sub>	9		
	Pulse (t = 1 ms) (Note 1)	I <sub>DP</sub>	27	Α	
Drain power dissipati	on (Tc = 25°C)	P <sub>D</sub>	150	W	
Single pulse avalanche energy (Note 2)		E <sub>AS</sub>	413	mJ	
Avalanche current		I <sub>AR</sub>	9	Α	
Repetitive avalanche energy (Note 3)		E <sub>AR</sub>	15	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55~150	°C	



Weight: 4.6 g (typ.)

#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	0.833	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	50	°C/W

Note 1: Please use devices on conditions that the channel temperature is below 150°C.

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- Note 2:  $V_{DD} = 90 \text{ V}$ ,  $T_{ch} = 25^{\circ}\text{C}(\text{initial})$ , L = 9.35 mH,  $I_{AR} = 9 \text{ A}$ ,  $R_G = 25 \Omega$
- Note 3: Repetitive rating: Pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device. Please handle with caution.

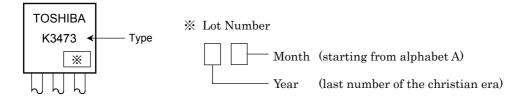
# **Electrical Characteristics (Ta = 25°C)**

Chara	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I <sub>GSS</sub>	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μΑ
Gate-source brea	akdown voltage	V (BR) GSS	$I_D = \pm 10 \; \mu A, \; V_{GS} = 0 \; V$	±30	_	_	V
Drain cut-off curre	ent	I <sub>DSS</sub>	V <sub>DS</sub> = 900 V, V <sub>GS</sub> = 0 V	_	_	100	μΑ
Drain-source brea	akdown voltage	V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	900	_	_	V
Gate threshold vo	oltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	2.0	_	4.0	V
Drain-source ON	resistance	R <sub>DS</sub> (ON)	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 4 A	_	1.3	1.6	Ω
Forward transfer	admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 4 A	3.0	6.5	_	S
Input capacitance		C <sub>iss</sub>	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	1450	_	pF
Reverse transfer capacitance		C <sub>rss</sub>		_	30	_	
Output capacitance		Coss		_	155	_	
Switching time	Rise time	t <sub>r</sub>	$\begin{array}{c c} 10 \text{ V} & \text{I}_D = 4 \text{ A} & \text{V}_{OUT} \\ \hline \text{VGS} & \text{OV} & \text{OV} & \text{OV} \\ 4.7 \Omega & \text{S} & \text{RL} = \\ \text{VDD} \simeq 400 \text{ V} \end{array}$	_	30	_	
	Turn-on time	t <sub>on</sub>			55	_	no
	Fall time	t <sub>f</sub>			12		ns
	Turn-off time	t <sub>off</sub>	Duty $\leq$ 1%, $t_W = 10 \mu s$	_	75	_	
Total gate charge		Qg		_	38	_	
Gate-source charge		Q <sub>gs</sub>	$V_{DD} \simeq 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 9 \text{ A}$	_	22	_	nC
Gate-drain charge		Q <sub>gd</sub>		_	16	_	

# **Source-Drain Ratings and Characteristics (Ta = 25°C)**

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	_	_	_	9	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	_	27	Α
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = 9 A, V <sub>GS</sub> = 0 V	_	_	-1.7	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = 9 A, V <sub>GS</sub> = 0 V,	_	1350	_	ns
Reverse recovery charge	Q <sub>rr</sub>	dI <sub>DR</sub> /dt = 100 A/μs	_	15	_	μС

## Marking



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